

<b>Notice of References Cited</b>		Application/Control No. 10/526,794	Applicant(s)/Patent Under Reexamination SAIKA ET AL.	
		Examiner Anish Desai	Art Unit 1771	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,225,046 B1	05-2001	Vesey et al.	435/5
B	US-			
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Takeshi et al., "A Method for Testing Microorganisms On Solid Surface and Kit Therefor", English translation of JP 2002-142797A, 05/21/2002.
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.